

<b>Notice of References Cited</b>	Application/Control No. 10/665,679		Applicant(s)/Patent Under Reexamination HAYAISHI ET AL.	
	Examiner Paul Saunders		Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0081249 A1	05-2003	Ahmad et al.	358/1.15
*	B	US-7,034,878 B2	04-2006	Matsushima, Yuki	348/333.03
*	C	US-2003/0095197 A1	05-2003	Wheeler et al.	348/241
*	D	US-6,535,636 B1	03-2003	Savakis et al.	382/173
*	E	US-2003/0068100 A1	04-2003	Covell et al.	382/305
*	F	US-6,201,571 B1	03-2001	Ota, Takayuki	348/239
*	G	US-2003/0117511 A1	06-2003	Belz et al.	348/333.11
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1137248 A2	09-2001	European Patent	SCHILDKRAUT et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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